

<b>Notice of References Cited</b>		Application/Control No. 10/692,666	Applicant(s)/Patent Under Reexamination SHEN ET AL.	
		Examiner Mia M. Thomas	Art Unit 2624	Page 1 of 1

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*	B	US-4,792,979	12-1988	Nomura et al.	382/169
*	C	US-5,689,575	11-1997	Sako et al.	382/118
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*	G	US-2005/0185837	08-2005	Takano et al.	382/162
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chan et al. "An Improved Super Resolution with Manifold Learning and Histogram Matching" Spring Verlag Heidelberg 2005, pages 756-762
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.